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## SUPPORTING INFORMATION

**Figure 9.** Refractive index n (a) and extinction coefficient k (b) for the 9 layer-pairs of PDDA-NiPc are derived from experimentally measured  $\Psi$  and  $\Delta$  based on parametrized model (dashed lines) and direct method (solid lines). Note that there is some noise in refractive index n spectrum in the direct method.

Figure 10. Refractive index n (a) and extinction coefficient k (b) for the 3 layer-pairs of PDDA-NiPc are derived from experimentally measured  $\Psi$  and  $\Delta$  based on parametrized model (dashed lines) and direct method (solid lines). Note that there is some noise in both refractive index n and extinction coefficient k spectra in the direct method.







